

**Search Notes**

Application/Control No.

10/672,200

Examiner

Huyen Le

Applicant(s)/Patent under  
Reexamination

PARIKH ET AL.

Art Unit

3751

**SEARCHED**

Class	Subclass	Date	Examiner
401	25	3/1/2006	HL
	261		
	265		
	266		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
US-PGPUB		3/1/2006	HL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR